

Government Agencies Technology Exchange in Manufacturing (GATE-M)

MEETING SUMMARY

May 9, 2002

**at the National Institute of Standards and Technology (NIST)
Gaithersburg, Maryland**

Introductory Remarks

SUMMARY

- It was announced that Dale Hall, the GATE-M Panel Chair, would not be able to participate in the meeting due to the recent passing of his father.
- Attendees:
 - Dan Cundiff, DOD
 - Hank Kenchington, DOE EERE (via teleconference)
 - Nan Founds, DOE NNSA (via teleconference)
 - Roger Hayes, DOE NNSA
 - John Vickers, NASA (via teleconference)
 - George Hazelrigg, NSF
 - Bruce Kramer, NSF
 - Dave Stieren, NIST (acting Chair for Dale Hall)
 - Emily Ann Meyer, NRC
- Nan Founds was introduced to the Panel as the new DOE NNSA principal on the Panel, replacing John Tribou and representing the NNSA signatory, Julianne Levings.
- Roger Hayes was introduced to the Panel. He is the Chief Engineer within the DOE NNSA Office of Military Application and Stockpile Operations, reporting to Dave Beck, the Deputy Director of DOE Defense Programs. Roger co-represented NNSA during the meeting.
- Bruce Kramer was introduced to the Panel. Bruce is the Director of the NSF Division of Engineering and Education Centers. Bruce is the co-principal from NSF to the GATE-M Panel.
- Emily Ann Meyer from the National Research Council (NRC) was also introduced to the Panel. She was in attendance as a guest to speak with the Panel about an NRC Manufacturing Forum that is being planned for spring 2003. Emily works with Toni Marechaux at the NRC, who has previously interacted with the GATE-M Panel.

ACTIONS

- None identified.

GATE-M Priority Items

SUMMARY

- A presentation prepared by NIST was used to guide discussion of the manufacturing priority issues submitted by each agency
 - Each agency representative gave a description of his or her agency's issue submissions.
 - The initial analysis of these issues that was conducted by NIST was also discussed.
 - It was suggested that the issues submitted by DOE EERE be used as a temporary placeholder until it was possible for the EERE principal to flesh out more specific manufacturing components from the high-level agency mission-related issues that it submitted.
- As the Panel reviewed the NIST analysis process, the Panel decided to focus discussion on those issues in which multiple agencies had interest.
 - This discussion surfaced the fact that most of the 37 total issues submitted by the agencies resonated across more than one agency, whether a specific agency submitted the issue as a priority or not.
 - It was decided that an appropriate next step would be to link together similar issues, capturing common attributes of those issues, then summarize the grouped focus areas and distribute this information to the Panel for review.
- After linking and summarizing similar issues into a smaller, more manageable list, the Panel decided that the next meeting would focus on discussion of these grouped areas, leading to a prioritization of those areas. This would in turn lead to the identification of some (small) number of issues that GATE-M would address jointly.

ACTIONS

- Prior to the next GATE-M meeting, NIST will re-address the issues to group them, identify common attributes, and summarize the grouped focus areas. This will be distributed to the Panel prior to the next meeting.
- Prior to the next GATE-M meeting, NSF will re-address and summarize the grouped focus area of Education. This will be distributed to the Panel prior to the next meeting.
- As soon as possible, DOE EERE will re-address its submissions to determine whether any changes are necessary in accordance with the identification of specific manufacturing components of their submitted issues.

SUMMARY

- Emily Ann Meyer from the NRC described a biannual Manufacturing Forum that is being planned for spring 2003 and being sponsored by NIST.
 - This manufacturing event would be similar to the biannual NRC Materials Forum, but be held in the alternate, odd-numbered years.
 - The event would be high-level and broadly focused to attract members of Congress and their staff, executive level representatives from the Cabinet Departments of the federal government, and key executive decision makers from industry and academia.
 - Emily Ann distributed to the Panel the proposal sent by the NRC to NIST for this Manufacturing Forum, along with relevant material from previous Materials Forums.
- There was discussion about the planning committee that is being created for the event, and the NRC is soliciting from the GATE-M Panel suggestions of high-level, well-known and well-respected manufacturing personnel to serve on this planning committee.

ACTIONS

- As appropriate and as soon as possible, each agency is invited to submit suggestions of persons that might participate on the planning committee for this event. Suggestions can either be sent to Toni Marechaux or Emily Ann Meyer at the NRC (tmarecha@nas.edu or emeyer@nas.edu), or to Dale Hall or Dave Stieren at NIST (dale.hall@nist.gov or david.stieren@nist.gov).

Charter Update

SUMMARY

- The current status of the signature process for the GATE-M charter was discussed.
 - As of the date of this meeting, the only signature on the charter was that of Dale Hall of NIST.
 - Each agency described where they stand with respect to signing the charter, and the importance of getting this document signed in a timely fashion was agreed to by all.

ACTIONS

- Since the May 9 meeting and current as of early June, the charter signature will be conducted as follows:
 - NIST: charter signed and forwarded to the DOD the first week of June.
 - DOD: signatory changed due to a re-organization, but the DOD signature is expected to be completed in mid-June.

- NASA: receive charter from DOD, and have indicated that the NASA signature should be turned around quickly.
- DOE NNSA: receive charter from NASA, and have indicated that the NNSA signature should be turned around quickly.
- DOE EERE: receive charter from DOE NNSA and have indicated that EERE will sign as soon as their reorganization is complete, which should occur by the end of June.
- NSF: receive charter from DOE EERE and hope to be able to sign expeditiously; will forward completely signed charters to NIST, who will in turn forward an original, completely signed copy of the charter to each agency.

Other Business

SUMMARY

- The GATE-M session at the SAE Aerospace Manufacturing Technology Conference in Hartford, CT, on June 5 was announced. John Vickers of NASA, Dan Cundiff of DOD, and Dave Stieren of NIST are the speakers who represented GATE-M and their respective agencies at this session.
- The GATE-M website, which is under construction on a NIST-hosted server, was mentioned and will be included for discussion at a future GATE-M meeting.

ACTIONS

- NIST will schedule the next GATE-M meeting for the July/August timeframe, targeting an all-day meeting in Gaithersburg focused primarily on the prioritization of the manufacturing issues for GATE-M to jointly address.
- NIST will include an agenda item on the next GATE-M meeting to discuss the GATE-M website.